Applicant:

Leonard Forbes et al.

Title:

DEAPROM AND TRANSISTOR WITH GALLIUM NITRIDE OR GALLIUM ALUMINUM NITRIDE GATE

Docket No.:

303.355US4

Filed:

June 18, 2001

Examiner:

Unknown

Serial No.: 09/883,795

Due Date: N/A

Group Art Unit: 2814

Commissioner for Patents Washington, D.C. 20231

We are transmitting herewith the following attached items (as indicated with an "X"):

A return postcard.

Supplemental Preliminary Amendment (8 Pages).

A check in the amount of \$590.00 to cover the fee for additional claims as calculated below.

 $\frac{X}{X}$ Clean Version of Pending Claims (8 pgs.).

If an additional fee is required due to changes to the claims, the fee has been calculated as follows:

		CL	AIMS AS AMENDE	D		
	(1) Claims Remaining After Amendment		(2) Highest Number Previously Paid For	(3) Present Extra	Rate	Fee
TOTAL CLAIMS	35	-	20	15	x 18 =	\$270.00
INDÉPENDENT CLAIMS	7	-	3	4	x 80 =	\$320.00
[] MULTIPLE DEPENDENT CLAIMS PRESENTED						\$0.00
TOTAL						\$590.00

Please consider this a PETITION FOR EXTENSION OF TIME for sufficient number of Anonths of enter these papers and please charge any additional required fees or credit overpayment to Deposit Account N

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.

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CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on this  $18^{1/3}$  day of September, 2001.

Signature Um Marcat

**Customer Number 21186** 

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A. P.O. Box 2938, Minneapolis, MN 55402 (612-373-6900) (GENERAL)

**PATENT** S/N 09/883.795

IN THE UNITED STATES

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ALUMINUM NITRIDE GATE

DEAPROM AND TRAN

SUPPLEMENTAL PRELIMINARY AMENDMENT

Commissioner for Patents Washington, D.C. 20231

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Before taking up the above-identified application for examination, please enter the following amendments. Please substitute the claim set in the appendix entitled Clean Version of Pending Claims for the previously pending claim set.

## IN THE CLAIMS

Please amend the following claims and add claims 30-61:

(Amended) A method of forming a floating gate transistor[, the method] comprising: 24. forming a source region and a drain region[s] in a substrate;

forming a gate insulator [from the gate insulator material] comprising silicon dioxide (SiO<sub>2</sub>) on a channel region in the substrate between the source region and the drain region; and

forming a floating gate [from] comprising a floating gate material selected from the group consisting [essentially] of gallium nitride (GaN) and gallium aluminum nitride (GaAlN), such that the floating gate is isolated from conductors and semiconductors.

- (Amended) The method of claim 24[,] wherein forming [the] a floating gate [includes] 25. further comprises forming the floating gate by depositing the floating gate material by metal organic chemical vapor deposition (MOCVD).
- (Amended) The method of claim 24[,] wherein forming [the] a floating gate [includes] 26. further comprises forming the floating gate material by plasma-enhanced molecular beam epitaxy (PEMBE).

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